

Transverse Beam Profiling and Vertical Emittance Control with a Double-Slit Stellar Interferometer



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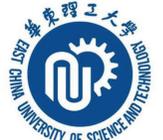
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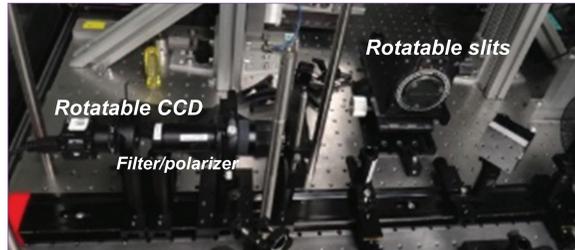
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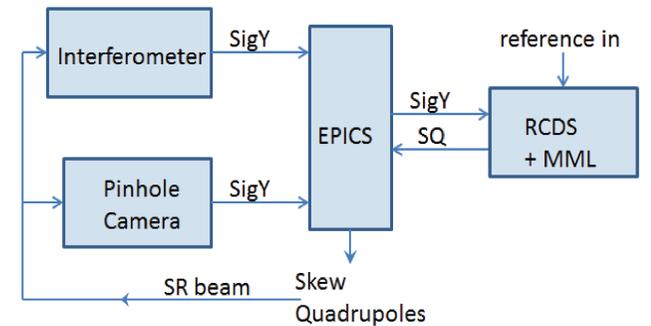
Abstract

- Double-slit stellar interferometer measures the transverse size of relativistic charged particle beams
- Describe the double-slit interferometer at SPEAR3 and develop a theoretical framework for the interferometer
- Rotating the double-slit, the transverse beam profile can be reconstructed including beam tilt at the source.
- Demonstrate the use of the SPEAR3 visible-light interferometer for emittance control using the Robust Conjugate Direction Search (RCDS) optimal search algorithm.

Rotating interferometer slits

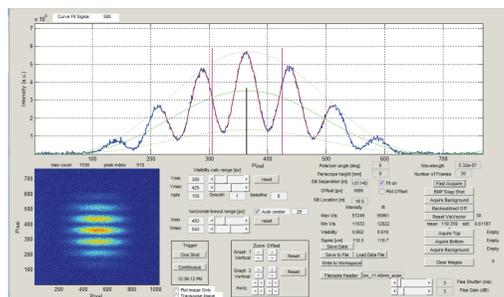
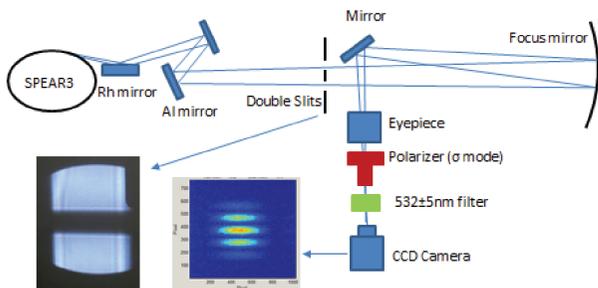


Robust Conjugate Direction Search for vertical beam size control (RCDS)



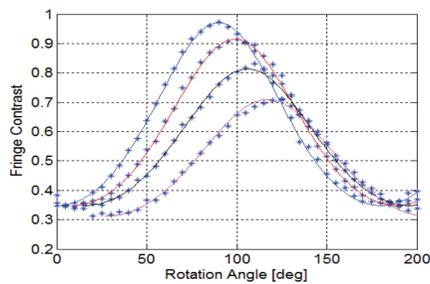
Architecture for RCDS experiment. Vertical interferometer and pinhole camera report σ_y to EPICS. RCDS calculates skew quad settings to control σ_y .

SPEAR3 Interferometer System

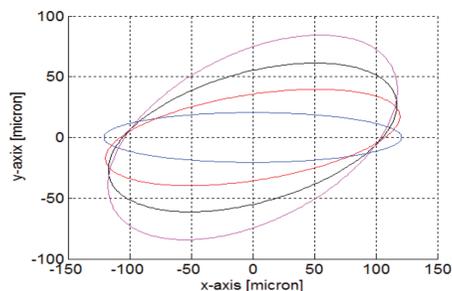


- 20um x 120um source point
- 60mm x 150mm unfocused beam
- 150mm reflective mirror: f=+120mm
- Commercial telescope objective
- Double slit and CCD camera on rotation stages
- Matlab analysis interface + MML to EPICS

Measurement Results

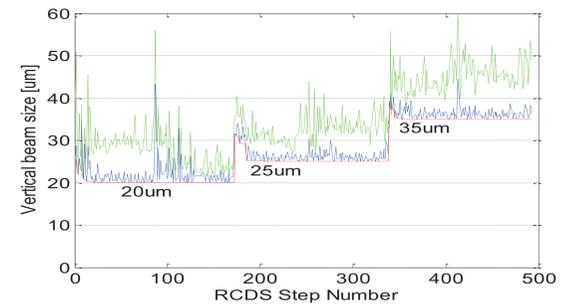


Contrast measurement and fit with double-slit rotation. Four different coupling conditions

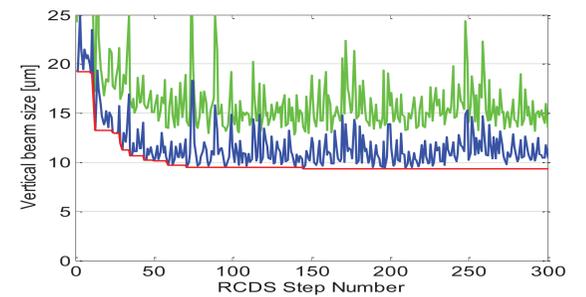


RMS electron beam cross-section for each coupling condition

Measurement Results

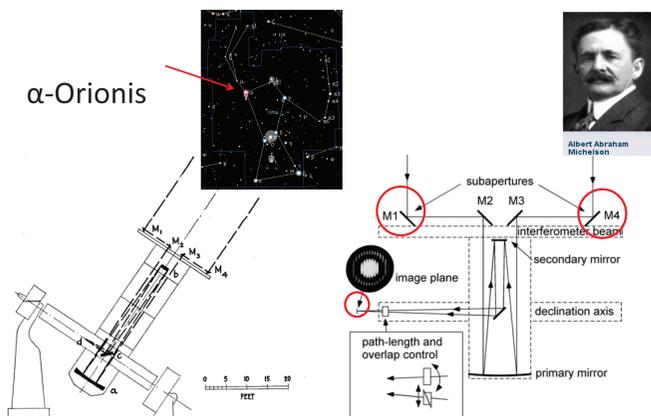


Vertical beam size reference set to 20um, 25um and 30um at the interferometer (blue). Pinhole camera in green



Reduction to $\sigma_y=9.5 \mu\text{m}$ with RCDS objective function set to zero

Michelson Stellar Interferometer (1920)



- For Michelson's interferometer, the ratio between α -Orionis diameter and distance to telescope was $\sim 1 \times 10^{-7}$
- For SPEAR3, the ratio is $\sim 1.7 \times 10^{-6}$

Van Cittert-Zernike relation in a Rotated Coordinate System

$$\gamma(f_x, f_y) = \iint I(x, y) e^{i2\pi(f_x x + f_y y)} dx dy$$

For a Gaussian beam in the x-y plane

$$I(x, y) = I_0 e^{-\left(\frac{x^2}{2\sigma_x^2} + \frac{y^2}{2\sigma_y^2}\right)}$$

$$\gamma(f_x, f_y) = e^{-\left(\frac{f_x^2}{2\sigma_{\gamma,x}^2} + \frac{f_y^2}{2\sigma_{\gamma,y}^2}\right)}$$

$f = \frac{d}{\lambda L} m^{-1}$ = the spatial frequency

d-slit separation

L-source-to-slit distance

Rotating the double slits by angle θ

$$f_x = \frac{d}{\lambda L} \cos\theta \text{ and } f_y = \frac{d}{\lambda L} \sin\theta$$

The coherence function becomes

$$\gamma(f_x, f_y, \theta) = e^{-\left(\frac{\left(\frac{d}{\lambda L} \cos\theta\right)^2}{2\sigma_{\gamma,x}^2} + \frac{\left(\frac{d}{\lambda L} \sin\theta\right)^2}{2\sigma_{\gamma,y}^2}\right)}$$

Summary

- SPEAR3 has a diagnostic beam line with unfocused visible light 16m from the source
- Rotation of the double-slit mask with respect to the beam axis yields a modulated fringe contrast profile in agreement with theory
- The interferometer was applied as a measurement tool to control vertical electron beam size using the Robust Conjugate Directional Search algorithm (RCDS)

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